

## TEST REPORT EN 60947-2

## Low-voltage switchgear and controlgear - Part 2: Circuit-breakers

Report Number. ....: (2023)FQIIDQCE-0331

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Total number of pages .....: 28

Name of Testing Laboratory Fujian Inspection and Research Institute for Product Quality

preparing the Report....: (FQII)

Applicant's name ...... Zhejiang Tengen Electric Co., Ltd.

Address ...... Sulv Industrial Area, Liushi Town, Yueqing City, Zhejiang

Province, P.R.China

Test specification:

Standard .....: EN 60947-2:2017,EN 60947-2:2017/A1:2020

Non-standard test method .....: N/A

Test Report Form No. .....: IEC60947\_2K

Test Report Form(s) Originator..: DEKRA Certification B.V.

Master TRF .....: Dated 2023-09-14

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Test item description .....: CBR

Trade Mark(s).....: TENGEN

Manufacturer .....: Zhejiang Tengen Electric Co.,Ltd. /

Sulv Industrial Area, Liushi Town, Yueqing City, Zhejiang

Province, P.R.China

Model/Type reference .....: TGM3L-250L, TGM3L-250M, TGM3L-250H

Ratings : Uimp:8kV;Ui:800V;Ue:AC400V;

In:100A,125A,140A,160A,180A,200A,225A,250A;

Type of over-current release: Thermo-magnetic, electro-

magnetic;

TGM3L-250L:lcs:26kA,lcu:35kA; TGM3L-250M: lcs:50kA,lcu:50kA; TGM3L-250H:lcs:50kA, lcu:65kA; l△n: 30mA(without time-delayed type)/

50mA/75mA/100mA/150mA/200mA/ 300mA/400mA/500mA

(Optional three by fixed steps or one fixed)/ Type AC;

t≤0.2s(without time-delayed type),

 $\triangle$ t:0.1s/ 0.2s/0.3s/0.4s/ 0.5s/0.6s/ 0.7s/0.8s

(Time-delayed type)(Optional three by fixed steps or one fixed); Type of residual current release:Electronic; I△m:25%lcu; Selectivity:A; 3P,3P+N(Type A,3 protected poles with an uninterrupted neutral pole;Type D,3 protected poles with a protected uninterrupted neutral pole),4P(Type B,3 protected poles with a switched neutral pole;Type C,4 protected poles);

3P,4P:Suitable for isolation; 3P+N:Not suitable for isolation; Matching auxiliary contact FC34-250: 1NO1NC,2NO2NC,4NO4NC;lth:3A; Ui:690V;

AC-15: (380/400)V/0.3A,DC-13:(220/230)V/0.15A;

Electronic accessory complying with annex N:

Undervoltage release:QT34-250, Us:AC(220/230)V,AC(380/400)V;

Motor-operator: CD2-250, Us:AC(220/230)V,AC(380/400)V.

Responsible Testing Laboratory (as applicable), testing procedure and testing location(s):			
	CB Testing Laboratory:	Fujian Inspection and I Quality(FQII)	Research Institute for Product
Testii	ng location/ address:	Fuzhou, Fujian 350002	d, Hongshan,Gulou District, China & No.101,Baozhen strict,Fuzhou,Fujian 350015
Teste	d by (name, function, signature):	Xu Jiafeng (Engineer)	1934 1939)
Appr	oved by (name, function, signature) :	Wei Yunming (Chief Engineer)	Co Fring
	Testing procedure: CTF Stage 1:		
Testi	ng location/ address:		
Tested by (name, function, signature) :			
Approved by (name, function, signature) :			
	Testing procedure: CTF Stage 2:		
Testing location/ address:			
Tested by (name + signature):			
Witne	essed by (name, function, signature) :		
Appr	oved by (name, function, signature):		
		,	
	Testing procedure: CTF Stage 3:		
	Testing procedure: CTF Stage 4:		
Testing location/ address:			
Tested by (name, function, signature) :			
Witnessed by (name, function, signature) :			
Approved by (name, function, signature) :			
Supervised by (name, function, signature)			